

Wednesday, April 17

International Conference Hall (4F)		
10:00	Ceremony	10:00
10:40		10:40
10:40	Keynote Lecture I The Role of Packaging and System Integration in Future Compute Platforms Bruno Michel, IBM Research Laboratory / Switzerland Chairs: Toyohiro Aoki, IBM Japan, Yasumitsu Orii, Nagase	10:40
11:40		11:40
11:40	Keynote Lecture II Technology Trend of Flash Memory and New Memory Susumu Yoshikawa, Toshiba Memory Corporation / Japan Chairs: Kazuya Okamoto, Yamaguchi University, Eiji Higurashi, AIST	11:40
12:40		12:40
12:40	Lunch	12:40
13:40		13:40
13:40	Keynote Lecture III GPU: the Key Processor for AI and Supercomputing Toru Baji, NVIDIA / Japan Chairs: Akitsu Shigetou, NIMS, Jun Mizuno, Waseda University	13:40
14:40		14:40
14:40	Keynote Lecture IV Heterogeneous Integration on Fanout Packages Shin-Puu Jeng, Taiwan Semiconductor Manufacturing Company, Ltd. / Taiwan Chairs: Yasumitsu Orii, Nagase, Shiigenori Aoki, LINTEC	14:40
15:40		15:40
15:40	Poster Session / Break (3F)	15:40
16:40		16:40

	Room A (3F)	Room B (3F)	Room C (3F)	Room D (3F)	Room E (3F)	
16:40	WA1: iNEMI Session Chairs: Yoshihiro Tomita, Intel, Kazuya Okamoto, Yamaguchi University WA1-1 <Session Invited> Packaging Technology Roadmap and Electronics Manufacturing Challenges and Opportunities Benowitz Marc, Tsuriya Masahiro, International Electronics Manufacturing Initiative / USA WA1-2 Benchmarking of Qualification Methodologies for New Package Technologies and Materials Curtis Grosskopf ¹ , Feng Xue ² , David Locker ³ , Sven Thomas ¹ , Jiayu Zheng ¹ , Masahiro Tsuriya ¹ , ¹ IBM Systems Supply Chain Engineering / USA, Singapore, China, ² US Defense Department / USA, ³ Heraeus Deutschland GmbH & Co. KG / Germany, ⁴ iNEMI / Japan WA1-3 Inspection / Metrology Evaluation of Fine Pitch Test Vehicles for Advanced Packages Feng Xue ¹ , Joe Zou ² , Cindy Han ¹ , Charles Reynolds ¹ , Thomas Wassick ¹ , Glenn Pomerantz ¹ , Jason Frankel ¹ , Ravi Bonam ¹ , Charles Woychik ¹ , Masahiro Tsuriya ¹ , ¹ IBM Systems Supply Chain Engineering / Singapore, ² Intel / USA, ³ Wistron Corp. / Taiwan, ⁴ IBM Systems Packaging Development / USA, ⁵ IBM Research / USA, ⁶ T3 Electronics, Inc / USA, ⁷ iNEMI / Japan WA1-4 Molded Electronic Package Warpage Predictive Modelling Methodologies Ong, Kang Eu ¹ , Wei Keat Loh ¹ , Ron W. Kulterman ² , Chih Chung Hsu ¹ , Jenn An Wang ³ , Haley Fu ⁴ , ¹ Intel Technology Sdn. Bhd. / Malaysia, ² Flex Ltd / USA, ³ CoreTech System / Taiwan, ⁴ iNEMI / China	WB1: Pan Pacific Micro Electronics Symposium Sponsored Session Chairs: Charles E. Bauer, TechLead Corporation, Yasumitsu Orii, Nagase WB1-1 <Special Speech> [50min] Moore's Law for Packaging to Replace Moore's Law for ICs Rao R. Tummala, Georgia Institute of Technology / USA WB1-2 <Session Invited> Wearables & Implantables: How Technology Transforms Health Care ... How Health Care Transforms Technology Matthew Hudes, bdl Bilology / USA WB1-3 <Session Invited> 3D & Printed Electronics Manufacturing Strategies Chris Bailey, University of Greenwich / United Kingdom	WC1: Taiwan Session Chairs: Shoji Uegaki, E-ThermoGentek, Jun Mizuno, Waseda University WC1-1 <Session Invited> A Novel Wafer-Level Package for New Wave MEMS Jeff Kuo, ASE Group / Taiwan WC1-2 <Session Invited> Low-Temperature Lead-Free Solders: Phase Equilibria and Interfacial Reactions Shih-kang Lin, National Cheng Kung University / Taiwan WC1-3 <Session Invited> Fabrication of Advanced Microelectronic Interconnections with the Assistance of Light Irradiations Jenn-Ming Song, National Chung Hsing University / Taiwan WC1-4 <Session Invited> Enhancement of Nano-Silver Chip Attachment by Using Transient Liquid Phase Reaction with Indium C. Robert Kao, National Taiwan University / Taiwan	WD1: Materials and Processes-1 Chairs: Koichi Hirano, Panasonic, Tetsuya Onishi, Grand Joint Technology WD1-1 An Investigation of Compound Machining of Ceramic-LPM Package by Ultrafast Laser Shih-jeh Wu ¹ , Hsiang-Chen Hsu ^{2,3} , Wen-Fei Lin ¹ , Yeh Chang ¹ , Ching-Pin Yen ¹ , ¹ I-Shou University, ² St. John's University / Taiwan WD1-2 Evaluation and Benchmarking of Cu Pillar Micro-Bumps with Printed Polymer Core Xing Qiu ¹ , Jeffery C. C. Lo ¹ , S. W. Ricky Lee ¹ , Ying-Hong Liou ² , Peter Chiu ¹ , ¹ Hong Kong University of Science & Technology / Hong Kong, ² DETEKT, Tu-Cheng District / Taiwan WD1-3 Highly Reliable Four-Point Bending Test Using Stealth Dicing Method for Adhesion Evaluation Yi-Lun Yang ^{1,2} , Jia-Ling Liu ² , Guan Wei Chen ² , Shoichi Kodama ^{1,3} , Kyosuke Kobinata ^{1,3} , Kuan-Neng Chen ^{1,2} , Hiroyuki Ito ¹ , Young Suk Kim ^{1,3} , Takayuki Ohba ¹ , ¹ Tokyo Institute of Technology / Japan, ² National Chiao Tung University / Taiwan, ³ DISCO Corporation / Japan WD1-4 X-ray Radiolysis-Based Three Dimensional Additive Manufacturing Process S. Saegusa ¹ , I. Sakurai ² , I. Okada ² , T. Fukuoka ¹ , S. Suzuki ¹ , Y. Utsumi ¹ , A. Yamaguchi ¹ , ¹ University of Hyogo, ² Nagoya University / Japan	WE1: Thermal-Management-1 Chairs: Hitoshi Sakamoto, Huawei Technologies Japan, Tomoyuki Hatakeyama, Toyama Prefectural University WE1-1 From Package to System Thermal Characterization and Design of High Power 2.5-D IC Huang Hung-Hsien, Cheng-Yu Tsai, Jung-Che Tsai, Meng-Kai Shih, David Tang, CP Hung, ASE Inc. / Taiwan WE1-2 An Enhanced Vapor Chamber using Dielectric Organic Refrigerant Mahiro Hachiya, Minoru Yoshikawa, NEC Corporation / Japan WE1-3 Heatsink Design Using Spiral-fins Considering Additive Manufacturing Shingo Otake ¹ , Yoshihiro Tateishi ¹ , Hiromichi Gohara ² , Ryoichi Kato ² , Yoshinari Ikeda ² , Victor Parque ¹ , Muhammed Khairi Faiz ¹ , Makoto Yoshida ¹ , Tomoyuki Miyashita ¹ , ¹ Waseda University, ² Fuji Electric Co., Ltd. / Japan	16:40
18:20						18:20
19:00	Welcome Reception (Hotel Nikko Niigata 4F)					19:00
21:00						21:00

Thursday, April 18

International Conference Hall (4F)		
9:00	Keynote Lecture V Technical Issues on Micro Display with GaN-Based Micro LEDs Tohru Honda, Kogakuin University / Japan Chairs: Atsushi Okuno, Green Planets Co., Ltd., Yoshio Nogami, Toray Engineering	9:00
9:50		9:50
9:50	Keynote Lecture VI Printing in the Third Dimension; Design, Materials, Equipment & Applications in Electronics Charles E. Bauer, TechLead Corporation / USA Chairs: Osamu Suzuki, NAMICS, Yasumitsu Orii, Nagase	9:50
10:40		10:40
10:40	Break (3F)	10:40
11:00		11:00

	Room A (3F)	Room B (3F)	Room C (3F)	Room D (3F)	Room E (3F)	
11:00	<p>TA1: Advanced Packaging-1 Chairs: Yoshihiro Tomita, Intel, Masahiro Aoyagi, AIST</p> <p>TA1-1 Copper-to-Copper Direct Bonding Using Different (111) Surface Ratios of Nanotwinned Copper Films J. W. Huang, K. C. Shie, H. C. Liu, Y. J. Li, H. Y. Cheng, C. Chen, National Chiao Tung University / Taiwan</p> <p>TA1-2 Investigation of Mechanism of Corrosion Resistance of Pd Coated Cu Wire Joint by Pseudo Process Shunsuke Nemoto¹, Takehiko Maeda¹, Masahiro Miyajima¹, Yasuhiko Akaike¹, Katsuhiko Kitagawa¹, Hideki Ishii¹, Haruo Shimamoto², Katsuya Kikuchi², Renesas Electronics Corporation, ²AIST / Japan</p> <p>TA1-3 Direct Bonding with Ni-P Finished DBC Substrate with Sinter Ag Micro-sized Particles Chuantong Chen, Zheng Zhang, Takuya Misaki, Shijo Nagao, Katsuaki Suganuma, Osaka University / Japan</p> <p>TA1-4 Development of Stretchable Conductive Adhesive for Flexible Hybrid Electronics (FHE) Masayoshi Otomo¹, Irma Yolanda Kapoglis², Noriyuki Sakai¹, ¹NAMICS Corporation / Japan, ²Diemat, Inc. / USA</p>	<p>TB1: High-Speed, Wireless & Components Chairs: Keiju Yamada, Toshiba, Shuji Sagara, DNP</p> <p>TB1-1 <Session Invited> Development of C Band Phased Array Single Element using Multi-material Printing Susan C. Trulli¹, Alkim Akylurtlu², Elicia K. Harper¹, Dmytro Volkov², Craig Armiento^{1,2}, Christopher Loughton¹, Raytheon Integrated Defense Systems, ²University of Massachusetts / USA</p> <p>TB1-2 A High Signal-Integrity PCB-Trace with Embedded Chip Capacitors and Its Design Methodology Using Genetic Algorithm Moritoshi Yasunaga, Shumpei Matsuoka, Yuya Hoshinor, Takashi Matsumoto, Tetsuya Odaira, University of Tsukuba / Japan</p> <p>TB1-3 High-speed High-Density Cost-Effective Cu-Filled Through-Glass-Via Channel for Heterogeneous Chip Integration Hiroshi Kudo, Miyuki Akazawa, Shouhei Yamada, Masaya Tanaka, Haruo Iida, Junya Suzuki, Takamaso Takano, Satoru Kuramochi, DNP Co., Ltd. / Japan</p> <p>TB1-4 A Low-Cost Antenna-in-Package Solution for 77GHz Automotive Radar Applications Cheng-Yu Ho, Sheng-Chi Hsieh, Ming-Fong Jhong, Hung-Chun Kuo, Chun-Yen Ting, Chen-Chao Wang, ASE, Inc. / Taiwan</p>	<p>TC1: Fan Out Technology-1 Chairs: Toshihisa Nonaka, Hitachi Chemical, Kouichi Hasegawa, JSR</p> <p>TC1-1 <Session Invited> [50min] Key Developments in FO-WLP and Emerging Trends in Large Area Processing Jan Vardaman, TechSearch International, Inc. / USA</p> <p>TC1-2 <Session Invited> Panel RDL Substrate for High Density Interconnection Yu-Hua Chen, Unimicon Technology Corp / Taiwan</p> <p>TC1-3 Trace line Layout Design of FO-WLCSP Yih-Ting Shen, Yu-Hsiang Liu, Kuo-Ning Chiang, National Tsing Hua University / Taiwan</p>	<p>TD1: Materials and Processes-2 Chairs: Akitsu Shigetou, NIMS, C. Robert Kao, Natinal Taiwan University</p> <p>TD1-1 What Happens To Low TCE Copper With Annealing Kazuo Kondo, Fine Feature Electrodeposition Research Laboratory / Japan</p> <p>TD1-2 Effects of Electroless Copper Plating on Crystal Continuity in Via Bottom Yuhei Kitahara, Joonhaeng Kang, Okuno Chemical Industries Co., Ltd. / Japan</p> <p>TD1-3 A Cu-Cu Bonding Method Using Preoxidized Cu Microparticles under Formic Acid Atmosphere Runhua Gao, Jiahui Li, Yu-An Shen, Hiroshi Nishikawa, Osaka University / Japan</p> <p>TD1-4 R2R Nano-Patterning Technology Using 250 mm- Wide Seamless Roller Mold Kazuma Komatsu¹, Masayuki Abe¹, Naoto Ito¹, Shinji Matsui², ¹Asahi Kasei Corporation, ²University of Hyogo / Japan</p>	<p>TE1: Thermal Management-2 Chairs: Hitoshi Sakamoto, Huawei Technologies Japan, Tomoyuki Hatakeyama, Toyama Prefectural University</p> <p>TE1-1 <Session Invited> Evaluation of Heat Dissipation Performance of PCB Using JPCA Method Tomoyuki Hatakeyama, Risako Kibushi, Masaru Ishizuka, ¹Toyama Prefectural University, ²Sanyo-Onoda City University / Japan</p> <p>TE1-2 Integration of GaN-SiC and GaN-Diamond by Surface Activated Bonding Methods Fengwen Mu, Tadatomo Suga, The University of Tokyo / Japan</p> <p>TE1-3 How TIM Impacts Thermal Performance of Electronics: A Thermal Point of View Study to Understand Impact of Thermal Interface Material (TIM) Tejas Manohar Kesarkar, Nitesh Kumar Sardana, Robert Bosch Engineering and Business Solutions Pvt. Ltd. / India</p>	11:00
12:40	Lunch Time					12:40
12:40	Lunch Time					12:40
13:40	<p>TA2: Power Electronics Integration-1 Chairs: Tetsuya Onishi, Grand Joint Technology, Yoshitaka Nishimura, Fuji Electric</p> <p>TA2-1 Processing and Characterization of Die-attach on Uncoated Copper by Pressure-less Silver Sintering and Low-pressure-assisted Copper Sintering Meiyu Wang¹, Yanliang Shan¹, Yunhui Mei¹, Xin Li¹, Guo-Quan Lu^{1,2}, ¹Tianjin University / China, ²Virginia Tech / USA</p> <p>TA2-2 Heat Resistant Cu-Sn based Joint Paste for less than 30µm joint thickness Hiroaki Ikeda, Shigenobu Sekine, Ryuyi Kimura, Koichi Shimokawa, Keiji Okada, Hiroaki Shindo, Tatsuya Ooi, Rei Tamaki, Napra Corporation / Japan</p> <p>TA2-3 Direct Power Board Bonding Technology for 3D Power Module Package. Hidetoshi Ishibashi, Hiroshi Yoshida, Daisuke Murata, Shota Morisaki, Hodaka Rokubuchi, Ayumi Minamide, Nobuhiro Asaji, Mitsubishi Electric Corporation / Japan</p>	<p>TB2: Emerging Technologies-1 Chairs: Nobuaki Hashimoto, Suwa University of Science, Yu Kondo, OLYMPUS</p> <p>TB2-1 Room Temperature Bonding of Smooth Au Surface of Electroformed Cu Substrate in Atmospheric Air Takashi Matsumae¹, Michitaka Yamamoto², Yuichi Kurashima¹, Eiji Higurashi¹, Hideki Takagi¹, ¹AIST, ²The University of Tokyo / Japan</p> <p>TB2-2 A Single Process for Homogeneous and Heterogeneous Bonding in Flexible Electronics Ethanol-Assisted Vacuum Ultraviolet (E-VUV) Irradiation Process T. H. Yang^{1,2}, C. Y. Yang¹, A. Shigetou¹, C. R. Kao¹, ¹National Taiwan University / Taiwan, ²NIMS / Japan</p> <p>TB2-3 Over-Voltage Protection Epoxy-CNT Composites Paul Czubarow¹, Yoshitaka Kamata², Toshiyuki Sato³, Howard Katz², ¹eM-TECH, Inc. / USA, ²NAMICS Corporation / Japan, ³Johns Hopkins University / USA</p> <p>TB2-4 Interconnect Fabrication Using Copper Oxide Particles by Photonic-sintering Po-Hsiang Chiu, Jenn-Ming Song, National Chung Hsing University / Taiwan</p>	<p>TC2: Fan Out Technology-2 Chairs: Toshihisa Nonaka, Hitachi Chemical, Yoichiro Sato, AGC</p> <p>TC2-1 <Session Invited> Pre Treatment Method Modification with Linear Ion Source for Fan Out Panel Level Packaging Tetsushi Fujinaga, ULVAC Inc. / Japan</p> <p>TC2-2 <Session Invited> Liquid Photolithographic Material Application Technique for FO-PLP in SCREEN FT Co., Ltd. Koichi Jono, SCREEN Finetech Solutions Co., Ltd. / Japan</p> <p>TC2-3 <Session Invited> [50min] FOCoS (Fanout Chip on Substrate) Solution for ASIC+ASIC and ASIC+HBM Teck Lee, ASE Group / Taiwan</p>	<p>TD2: Materials and Processes-3 Chairs: Kiyokazu Yasuda, Osaka University, Hiroshi Nishikawa, Osaka University</p> <p>TD2-1 Analysis of Bonding Interfaces of Pressureless-Sintered Cu on Metallization Layers Dai Ishikawa¹, Bao Ngoc An², Matthias Mail², Helge Wurst², Benjamin Leyrer², Thomas Blank², Marc Weber², Suguru Ueda¹, Hideo Nakako¹, Yuki Kawana¹, Hitachi Chemical Co., Ltd. / Japan, ²Karlsruhe Institute of Technology / Germany</p> <p>TD2-2 Novel Silver-Seed Semi-Additive Process for High Quality Circuit Formation Norimasa Fukazawa, Akira Murakawa, Wataru Fujikawa, Jun Shirakami, DIC Corporation / Japan</p> <p>TD2-3 Microstructural and Electrical Characteristics of Sintered Ag Interconnections through Different Reduction Methods Jen-Hsiang Liu, Yan-Jie Li, Jenn-Ming Song, National Chung Hsing University / Taiwan</p> <p>TD2-4 Development of Low-Temperature Sintering Materials for Bare Cu Lead-frame Kazuki Fukazawa, Noritsuka Mizumura, Satoshi Saito, Koji Sasaki, NAMICS Corporation / Japan</p>	<p>TE2: Interconnections-1 Chairs: Hiroshi Yamada, Toshiba, Kenji Takahashi, AIST</p> <p>TE2-1 Cu-Cu Quasi-Direct Bonding with Atomically Thin-Au and Pt Intermediate Layer Using Atomic Layer Deposition Hiroyuki Kuwae¹, Kosuke Yamada¹, Wataru Momose², Shuichi Shoji¹, Jun Mizuno^{1,3}, ¹Waseda University, ²ALD Japan, Inc. / Japan, ³Soochow University / China</p> <p>TE2-2 Low Resistance and High Reliable Cu-to-Cu Joints Using Highly (111)-Oriented Nano-Twinned Copper Jing Ye Juang¹, Kai Cheng Shie¹, Yu Jin Li¹, K N Tu^{1,2}, Chih Chen¹, ¹National Chiao Tung University / Taiwan, ²University of California at Los Angeles / USA</p> <p>TE2-3 Influence of Grain Refinement on Direct Bonding for Electrodeposited Copper Zong-Yu Xie¹, I-You Yu¹, Jenn-Ming Song¹, David Targ², Chih-Pin Hung², ¹National Chung Hsing University, ASE Group / Taiwan</p> <p>TE2-4 Bonding of Copper Pillars Using Electroless Cu Plating L. Y. Kao¹, H. T. Hung¹, Y. H. Chen², C. R. Kao¹, ¹National Taiwan University, ²Unimicon Corp. / Taiwan</p>	13:40
15:20	Poster Session / Break (3F)					15:20
15:20	Poster Session / Break (3F)					15:20
16:10	<p>TA3: Power Electronics Integration-2 Chairs: Toyohiro Aoki, IBM Japan, Yoshinari Ikeda, Fuji Electric</p> <p>TA3-1 3.3kV Power Module for Electric Distribution Equipment with SiC Trench-Gate MOSFET R. Takayanagi, K. Taniguchi, M. Hoya, N. Kanai, T. Tsuji, M. Hori, Y. Ikeda, K. Maruyama, I. Kawamura, Fuji Electric Co., Ltd / Japan</p> <p>TA3-2 Study of Gate Bias Voltage for Preventing Threshold Shift of SiC-MOSFET Body Diode during Transient Temperature Measurements Fumiki Kato¹, Shinji Sato¹, Kenichi Koui^{1,2}, Hidekazu Tanisawa^{1,3}, Hiroshi Hozoji¹, Hiroshi Yamaguchi¹, ¹AIST, ²Calsonic Kansei Corporation, ³Sankei Electric Co., Ltd. / Japan</p> <p>TA3-3 GaAs Diode Rectifier Power Module in Mixed Ag- and Large Area Cu-Sintering Technology for Ultra-Fast and Wireless Electric Vehicle Battery Charging Thomas Blank¹, Volker Dudek¹, Matthias Luh¹, Bao Ngoc An¹, Helge Wurst¹, Benjamin Leyrer¹, Dai Ishikawa¹, Marc Weber¹, ¹Karlsruhe Institute of Technology, ²3-5 Power Electronics GmbH / Germany, ³Hitachi Chemical Co., Ltd. / Japan</p>	<p>TB3: Emerging Technologies-2 Chairs: Yu Kondo, OLYMPUS, Nobuaki Hashimoto, Suwa University of Science</p> <p>TB3-1 Development of Compact and High-Efficient Simple CPW Rectenna for RF Energy Harvesting Mohamed M. Mansour^{1,2}, H. Kanaya¹, ¹Kyushu University / Japan, ²Electronics Research Institute / Egypt</p> <p>TB3-2 Electroencephalogram Measurement in Adapting Process to Inverse Vision Takeshi Onomoto, Y. Yoshida, N. Miki, Keio University / Japan</p> <p>TB3-3 Development of a Helmet-Type Wearable Device Capable of Measuring Perspiration During Various Activities Tsukasa Kosuda¹, Yoshiaki Nakajo¹, Konosuke Sasagawa¹, Yuto Nishikai², Shunji Shimizu¹, Yoshinori Kumita¹, Toshihiko Kondo¹, Nobuaki Hashimoto¹, ¹Suwa University of Science, ²Japan System Development Co., Ltd., ³Fujita Corporation, ⁴Kokankyo Engineering Corporation / Japan</p> <p>TB3-4 Long-Term in Vivo Experiment Protocol Using SD Rats Takahiro Ito, Y. Koya, N. Miki, Keio University / Japan</p>	<p>TC3: Embedded Technology Chairs: Toshihisa Nonaka, Hitachi Chemical, Kouichi Hasegawa, JSR</p> <p>TC3-1 <Session Invited> [50min] AiOP: The Packaging Solution of The Future? Markus Leitgeb, AT&S AG / Austria</p> <p>TC3-2 <Session Invited> [50min] Embedded Camera Module and System for Application of Automotive Hyunho Kim, Korea Jisso Industry Council / Korea</p>	<p>TD3: Materials and Processes-4 Chairs: Kiyokazu Yasuda, Osaka University, Hiroshi Ozaki, Sony Semiconductor Solutions</p> <p>TD3-1 <Session Invited> Friction Process and Microstructure Formation in Ultrasonic Bonding Tomohiro Sasaki, Niigata University / Japan</p> <p>TD3-2 Development of Electroless Ni-P Plating Film for Power Modules Norihiko Hasegawa, Kei Hashizume, Toshiya Murata, Okuno Chemical Industries Co., Ltd / Japan</p> <p>TD3-3 Barrier Properties of Electroless Deposit of Co-W-P Alloy Sho Kanzaki, Toshiaki Shibata, Seigo Kurosaka, Yukinori Oda, Shigeo Hashimoto, C.Uyemura & Co., Ltd. / Japan</p> <p>TD3-4 Surface Analyses of Oxidized Cu-Fe-Zn-P Lead Frames Shih-Chieh Chao¹, Jen-Hsiang Liu¹, Wei-Chen Huang¹, Jenn-Ming Song¹, Po-Yen Shen², Chi-Lin Huang², Lung-Tang Hung², Chin-Huang Chang², ¹National Chung Hsing University, ²Siliconware Precision Industries Co., Ltd. / Taiwan</p>	<p>TE3: Interconnections-2 Chairs: Jenn Ming Song, National Chung Hsing University, Masahisa Fujino, AIST</p> <p>TE3-1 Inhibition of Cracking in Cu₃Sn₅ Intermetallic Compounds at the Interface of Lead-Free Solder Joint by Controlling the Reflow Cooling Conditions Flora Somidin^{1,2}, Stuart D. McDonald¹, Xiaozou Ye¹, Dongdong Qu¹, Keith Sweatman¹, Tetsuya Akaiwa¹, Tetsuro Nishimura¹, Kazuhiro Nogita¹, ¹The University of Queensland / Australia, ²Universiti Malaysia Perlis (UniMAP) / Malaysia, ³Nihon Superior Co. Ltd. / Japan</p> <p>TE3-2 Optimization of Ag-Ag Direct Bonding for Wafer- Level Power Electronics Packaging via Design of Experiments Zechun Yu^{1,2}, Shize Wang², Sebastian Letz², Christoph Friedrich Bayer^{1,2}, Felix Häubler², Andreas Schletz², Katsuaki Suganuma², ¹Fraunhofer IISB, ²Friedrich-Alexander University / Germany, ³Osaka University / Japan</p> <p>TE3-3 Role of Bi, Sb and In in Microstructure Formation and Properties of Sn-0.7Cu-0.05Ni-X BGA Interconnections S. A. Belyakov¹, T. Nishimura¹, T. Akaiwa¹, K. Sweatman², K. Nogita¹, C. M. Gourlay¹, ¹Imperial College London / UK, ²Nihon Superior Co., Ltd / Japan, ³University of Queensland / Australia</p> <p>TE3-4 A Novel TLP Bonding Based on Sub-micron Ga Particles Shih-kang Lin, Hseng-ming Liao, Che-yu Yeh, Chih-han Yang, National Cheng Kung University / Taiwan</p>	16:10
17:50	International Reception (Hotel Nikko Niigata 31F) (Invite only)					17:50
18:30	International Reception (Hotel Nikko Niigata 31F) (Invite only)					18:30
20:30	International Reception (Hotel Nikko Niigata 31F) (Invite only)					20:30

Friday, April 19

International Conference Hall (4F)						
9:00	<p>IEEE EPS Special Speech Heterogeneous Integration Roadmap Chris Bailey, University of Greenwich / United Kingdom Chairs: Osamu Suzuki, NAMICS, Yasumitsu Orii, Nagase</p>				9:00	
9:25	<p>Emerging Technology Special Speech Neuromorphic Computing with Semiconductor Non-Volatile Memory Chung H Lam, Jianguo Advanced Memory Technology / China Chairs: Kiyokazu Yasuda, Osaka University, Yasumitsu Orii, Nagase</p>				9:25	
9:50	<p>Break (3F)</p>				9:50	
10:10	<p>Break (3F)</p>				10:10	
Room A (3F)	Room B (3F)	Room C (3F)	Room D (3F)	Room E (3F)		
10:10	<p>FA1: Fan Out Technology-3 Chairs: Yoichiro Sato, AGC, Kouichi Hasegawa, JSR</p> <p>FA1-1 Warpage and Simulation Analysis of Panel Level FO-WLCSP Using Equivalent CTE Shih-Wei Liu, Chia-Han Tsai, Kuo-Ning Chiang, National Tsing Hua University / Taiwan</p> <p>FA1-2 Surface-Modification Technology by Using Radical Shower Treatment (RST) Process in Submicron Interposer for Fan-out Packaging Applications. Takahide Murayama, Toshiyuki Sakuishi, Yasuhiro Morikawa, ULVAC, Inc. / Japan</p> <p>FA1-3 High-Toughness (111) Nano-Twinned Copper Lines for Fan-Out Wafer-Level Packaging Yu-Jin Li¹, Wei-Yu Hsu¹, Benson Lin², Chia Cheng Chang³, Chih Chen¹, National Chiao Tung University, ²PT, MediaTek Inc. / Taiwan</p> <p>FA1-4 High Speed Panel Level Metallization Technology Herbert Ötzlinger, Claudia Landstorfer, Tetsuya Onishi, Christian Dunkel, Raoul Schröder, Semsyco GmbH / Austria</p>	<p>FB1: Emerging Technologies-3 Chairs: Yasuhiro Morikawa, ULVAC, Noriyuki Fujimori, OLYMPUS</p> <p>FB1-1 Mechanical Characterization of FOWLP Based Flexible Hybrid Electronics (FHE) for Biomedical Sensor Application Yuki Susumago¹, Achille Jacquemond^{1,2}, Noriyuki Takahashi¹, Hisashi Kino¹, Tetsu Tanaka¹, Takafumi Fukushima¹, Tohoku University / Japan, ¹NSA Lyon / France</p> <p>FB1-2 Optimization of Wafer Thinning Process by Reducing Thickness Variation of Temporary Adhesive Layer for Medical Device Ken Yamamoto, Takuro Suyama, Noriyuki Fujimori, Olympus / Japan</p> <p>FB1-3 Programming and Evaluation of a Multi-Axis/Multi-Process Manufacturing System for Mechatronic Integrated Devices Markus Ankenbrand, Y. Eiche, J. Franke, Friedrich-Alexander University / Germany</p> <p>FB1-4 Gel-Integrated Mercury-Plated Microelectrode Arrays for Trace Metal Detection Zhi Cao^{1,2}, Haiping Shang², Yinghui Wang^{1,2}, Shengkai Wang^{1,2}, Weibing Wang^{1,2}, University of Chinese Academy of Sciences, Chinese Academy of Science / China</p>	<p>FC1: Flexible Hybrid Devices Chairs: Takashi Kasahara, Hosei University, Nobuaki Hashimoto, Suwa University of Science</p> <p>FC1-1 <Session Invited> Silicone Based Dielectric Elastomer Transducers and Robots Jun Shintake, The University of Electro-Communicat / Japan</p> <p>FC1-2 <Session Invited> The Ultra-Flexible Organic Electronics Tomoyuki Yokota, Takao Someya, The University of Tokyo / Japan</p> <p>FC1-3 <Session Invited> Self-Healing Metal Interconnect for Flexible Electronic Device Tomoya Koshi¹, Eiji Iwase², 1AIST,2Waseda University / Japan</p> <p>FC1-4 <Session Invited> Portable Analytical Detection Systems Based on Light Emitting Devices Ryoichi Ishimatsu, Kyushu University / Japan</p>	<p>FD1: Optoelectronics Chairs: Shigenori Aoki, LINTEC, Yasuhiro Ando, ABI Giken</p> <p>FD1-1 <Session Invited> Optical Transceiver Modules and Their Packaging Technologies for Data Center Applications Hideyuki Nasu, Furukawa Electric Co., Ltd.</p> <p>FD1-2 <Session Invited> Polymer Materials for Photonic Integrated Circuit Hideyuki Nawata, Nissan Chemical Corporation / Japan</p> <p>FD1-3 <Session Invited> Packaging Technologies for Chip-scale Silicon Photonic Transceivers Koichi Takemura¹, Kazuhiko Kurata², ¹PETRA, ²AIO Core Co., Ltd. / Japan</p> <p>FD1-4 <Session Invited> Planar Optical Circuits using Slab Optical Waveguide on SOI Substrate Takeo Maruyama, Kanazawa University / Japan</p>	<p>FE1: Design, Modeling, and Reliability-1 Chairs: Hitoshi Sakamoto, Huawei Technologies Japan, Masahiro Aoyagi, AIST</p> <p>FE1-1 Design Demonstration of Band-Pass-Filter Characteristics with Integrated Passive Device on Glass Interposer Masaya Tanaka, Takamasa Takano, Yumi Okazaki, Dai-Nippon Printing Co., Ltd. / Japan</p> <p>FE1-2 Gait Pattern Generation of Hexapod-Type Microrobot Using Interstitial Cell Model Based Hardware Neural Networks IC Mika Kurosawa, Takuro Sasaki, Masaya Ohara, Taisuke Tanaka, Yuichiro Hayakawa, Minami Kaneko, Fumio Uchikoba, Katsutoshi Saeki, Ken Saito, Nihon University / Japan</p> <p>FE1-3 Correlation between Insertion Loss and Interface Relative Conductivity Taiga Fukumori, Tomoyuki Akahoshi, Daisuke Mizutani, Seiki Sakuyama, Fujitsu Laboratories Ltd. / Japan</p> <p>FE1-4 Construction and Verification of Novel Insulation Defect Location System with High Space Resolution for Next Generation Power Module Junya Maki¹, Takakazu Matsuzoe¹, Masahiro Kozako¹, Masayuki Hikita¹, Yoko Nakamura², Katsumi Taniguchi², Yoshinari Ikeda², Kenji Okamoto², Kyushu Institute of Technology, ²Fuji Electric Co., Ltd / Japan</p>	10:10
11:50	<p>Lunch Time</p>				11:50	
12:50	<p>FA2: Power Electronics Integration-3 Chairs: Hiroshi Houzouji, AIST, Kenji Okamoto, Fuji Electric</p> <p>FA2-1 <Session Invited> Advanced Power Packaging Technology for High Power, High Frequency WBG Devices Yoshikazu Takahashi, Tetsuo Endoh, Tohoku University / Japan</p> <p>FA2-2 <Session Invited> Development of Highly Reliable Bonding Technologies and Its Application Yoshiyuki Nagatomo, Mitsubishi Materials Corporation / Japan</p> <p>FA2-3 <Session Invited> Recent Progress of SiC Power Devices and Their Futures Noriyuki Iwamura, University of Tsukuba / Japan</p> <p>FA2-4 <Session Invited> Potential of Non-Equilibrium Oxides of Ga₂O₃ and Ir₂O₃ for Power Device Applications Kentaro Kaneko¹, Takashi Shinohe², Shizuo Fujita¹, ¹Kyoto University, ²FLOFIA INC. / Japan</p>	<p>FB2: Emerging Technologies-4 Chairs: Yasuhiro Morikawa, ULVAC, Jun Mizuno, Waseda University</p> <p>FB2-1 <Session Invited> A Catch-and-Release drive MEMS Gyroscope for Low-Power Applications Yasushi Tomizawa, Ryunosuke Gando, Etsuji Ogawa, Kei Masunishi, Akiko Yuzawa, Tetsuro Itakura, Akihide Sai, Tamio Ikehashi, Toshiba Corporation / Japan</p> <p>FB2-2 Selective Removal by Laser Processing for the Sensor Mold Ryuta Ikoma, Kazuaki Mawatari, Koji Hashimoto, Junichi Sato, Nobuyoshi Wakasugi, Denso Corporation / Japan</p> <p>FB2-3 Integrated laser Doppler blood flowmeter combining optical contact force Hirofumi Nogami, Kosuke Komatsutani, Tomoki Hirata, Renshi Sawada, Kyushu University / Japan</p>	<p>FC2: Flexible Electronics-1 Chairs: Akitsu Shigetou, NIMS, Jenn-Ming Song, National Chung Hsing University</p> <p>FC2-1 <Session Invited> Ultraflexible Organic Differential Amplifier for Low-Noise Biosignal Monitoring Takafumi Uemura, Osaka University / Japan</p> <p>FC2-2 <Session Invited> Printing of Flexible Electronics for Wearable Applications Takeo Minari^{1,2}, Xuying Liu¹, Qingqing Sun¹, Wanli Li¹, Akitsu Shigetou^{1,2}, Masayuki Kanehara^{2,3}, ¹NIMS, ²Priways Co., Ltd., ³C-INK Co., Ltd. / Japan</p> <p>FC2-3 Homogeneous Dewetting on Large-Scale Microdroplet Arrays for Solution-Processing Electronics Qingqing Sun¹, Wanli Li¹, Xu-Ying Liu^{1,2}, Masayuki Kanehara¹, Takeo Minari¹, ¹NIMS, ²C-Ink. Co., Ltd / Japan, ³Zhengzhou University / China</p> <p>FC2-4 Air-stable Cu Complex Inks for Printed Electronics with High Conductivity and High Reliability Wanli Li¹, Qingqing Sun¹, Xu-Ying Liu¹, Katsuaki Sugauma², Takeo Minari¹, ¹NIMS, ²Osaka University / Japan</p>	<p>FD2: Korea Session-1 Chairs: Jun Shintake, The University of Electro- Communications, Shoji Uegaki, E-ThermoGentek</p> <p>FD2-1 <Session Invited> The Effects of Electrochemical Parameters on the Physical Properties of Ni Alloy Electroplating for MEMS Probe Card Jae-Ho Lee, Yong-Su Lee, Hong-Wook Chun, Hongik University / Korea</p> <p>FD2-2 <Session Invited> Stretchable and Self-Healable Electrode Comprising Silver Nanowires and Diels-Alder Sdducts Jong-Woong Kim, Chonbuk National University / Korea</p> <p>FD2-3 <Session Invited> IoT-Tag Module Development for LPWA Application. Gu-Sung Kim, EPRC / Korea</p> <p>FD2-4 <Session Invited> Organic-Based Silica Composite Aerogel with Ultralow Dielectric Constant and Thermal Conductivity Hyung-Ho Park, Yonsei University / Korea</p>	<p>FE2: Design, Modeling, and Reliability-2 Chairs: Hitoshi Sakamoto, Huawei Technologies Japan, Rickey Lee, Hong Kong University of Sci &Tech</p> <p>FE2-1 Reliability Assessment of WLCSP Using Energy Based Model with Inelastic Strain Energy Density Yu-Chen Lee, K. N. Chiang, National Tsing Hua University / Taiwan</p> <p>FE2-2 The Study of Sn-45Bi-2.6Zn Alloy Before and After Thermal Aging Shiqi Zhou¹, Chih-han Yang², Yu-An Shen¹, Shih-kang Lin², Hiroshi Nishikawa¹, ¹Osaka University / Japan, ²National Cheng Kung University / Taiwan</p> <p>FE2-3 Materials Informatics Technique for Designing Strong-Adhesion Interfaces in Electronics Devices Tomio Iwasaki, Hitachi, Ltd / Japan</p>	12:50
14:30	<p>Break (3F)</p>				14:30	
14:40	<p>FB3: LED Chairs: Yoshio Nogami, Toray Engineeing, Eiji Higurashi, AIST</p> <p>FB3-1 <Session Invited> LED Device Packaging Trend X-rays View Tetsuya Onishi, Grand Joint Technology Ltd. / China</p> <p>FB3-2 <Session Invited> Development and Manufacturing of The Near-Sunlight white LED Light Source using a Human-Friendly Violet LED Masaichi Kumikawa, Soraa / Japan</p> <p>FB3-3 <Session Invited> Unique Packaging Technology of High Bright LED, microLED, miniLED and UV LED using VPES Atsushi Okuno, Green Planets Co., Ltd / Japan</p> <p>FB3-4 <Session Invited> The Development of Micro-LED Technology in ITRI Yen-Hsiang Fang, Industrial Technology Research Institute / Taiwan</p> <p>FB3-5 <Session Invited> Introduction of AOI Machine using PL(Photoluminescence) and Laser Micro Trimming Machine for Micro LED Ayaka Okabe, Toray Engineering / Japan</p>	<p>FC3: Flexible Electronics-2 Chairs: Akitsu Shigetou, NIMS, Jenn-Ming Song, National Chung Hsing University</p> <p>FC3-1 <Session Invited> Molecular Design of Highly Reliable Low Dielectric Loss Materials Masao Tomikawa, Toray Industries Inc. / Japan</p> <p>FC3-2 <Session Invited> High-Performance Printed Carbon Nanotube TFTs and Circuits on Flexible Substrates Jianwen Zhao, Chinese Academy of Sciences / China</p> <p>FC3-3 <Session Invited> Solution-Synthesized p-Type Copper(I) Iodide Semiconductors for Transparent Thin-Film Transistors and Complementary Electronics Yong-Young Noh, POSTECH / Korea</p> <p>FC3-4 Room-Temperature Printing of CNTs-based Flexible TFTs with high Performance Qingqing Sun¹, Wanli Li¹, Xuying Liu^{1,3}, Masayuki Kanehara², Jianwen Zhao¹, Takeo Minari¹, ¹NIMS, ²Colloidal Ink. Co., Ltd. / Japan, ³Zhengzhou University, ⁴Chinese Academy of Sciences / China</p>	<p>FD3: Korea Session-2 Chairs: Hiroshi Yamaguchi, NAMICS, Shoji Uegaki, E-ThermoGentek</p> <p>FD3-1 <Session Invited> Fabrication of Ag-Based Hybrid/NanoComposite Pastes and Their Characteristics Choong-Jae-Lee, Kwang-Ho Jung, Bum-Geun Park, Seung-boo Jung, Sungkyunkwan university / Korea</p> <p>FD3-2 <Session Invited> Warpage Analysis of Flexible Electronics Taek-Soo Kim, KAIST / Korea</p>	<p>FE3: Health, Beauty and Technology Chairs: Yasumitsu Orii, Nagase, Shigenori Aoki, LINTEC</p> <p>FE3-1 <Session Invited> [50min] Do Chemical Reactions of Electronics Technologies and Cosmetics Occur? Yasuo Kato, Keio University / Japan</p> <p>FE3-2 <Session Invited> Innovations in Research and Development, Now and the Future-With a Focus on the Story Behind the Development of Wrinkle Shot Medical Serum- Hirotsuka Takeuchi, POLA Chemical Industries, Inc. / Japan</p> <p>FE3-3 <Session Invited> Possibility of Fusion: Cosmetic Research and Electronics Yukiko Ishitsuka, KOSE Corporation / Japan</p>	14:40	
16:45	<p>Break (3F)</p>				16:45	

Poster Session

Poster sessions will be held from 15:40-16:40 on April 17 and from 15:20-16:10 on April 18.

- P01 Effect Analysis of Application of Energy Band Gap to Electrostatic Discharge Protection**
Hong-Yin Hsieh, Jheng-Yuan Ruan, Min-Jun Guo, Wei-Chiao Wang, Sheng-Wei Guan, Sung-Mao Wu, National University of Kaohsiung / Taiwan
- P02 Au-Sn Soldering Using a Micro-heater to Restrain Excess Temperature Rise Inside the Package**
Hideaki Mizusaki, Toshiro Sato, Makoto Sonehara, Shinshu University / Japan
- P03 Thermo-Mechanical Process Emulation and Sensitivity Analysis of Wafer Warpage after Reconstitution in Fan-out Packaging**
Cheng-Ying Yang, Kuo-Shen Chen, Tian-Shiang Yang, Tz-Cheng Chiu, Ching-Jenq Ho, National Cheng-Kung University / Taiwan
- P04 Wafer-Scale Au-Au Surface Activated Bonding Using Atmospheric-pressure Plasma**
Michitaka Yamamoto^{1,2}, Takashi Matsumae², Yuichi Kurashima², Hideki Takagi², Toshihiro Miyake³, Tadatomo Suga¹, Toshihiro Itoh¹, Eiji Higurashi^{1,2}, ¹The University of Tokyo, ²AIST, ³DENSO Corporation / Japan
- P05 Nano-Cu Paste Sintering in Pt-Catalyzed Formic Acid Vapor for Cu Bonding at a Low Temperature**
Fengwen Mu¹, Hui Ren², Lei Liu², Yinghui Wang³, Guisheng Zou², Tadatomo Suga¹, ¹the University of Tokyo / Japan, ²Tsinghua University, ³University of Chinese Academy of Sciences / China
- P06 Development of Sn-Bi-In-Ga Quaternary low- Temperature Solders**
Chih-han Yang¹, Shiqi Zhou², Shih-kang Lin¹, Hiroshi Nishikawa², ¹National Cheng Kung University / Taiwan, ²Osaka University / Japan
- P07 Advanced Materials for Pathogenic Bacterial Sensing**
Dung Quang Nguyen, Kengo Ishiki, Maki Saito, Kota Iwamoto, Hiroshi Shiigi, Osaka Prefecture University / Japan
- P08 QFN Multi-Level Pin Routing: Innovative Design Approach Enabling Complex Wire Bonding Layout**
Dolores B. Milo, Texas Instruments Philippines / Philippines
- P09 Two-Faced Bondable Leadframe Design: Maximizing Leadframe Usage and Purpose**
Ernesto P. Rafael Jr., Dolores Babaran-Milo, Texas Instrument Philippines / Philippines
- P10 Mixed Mode Tension Test of Underfills**
Hiroshi Yamaguchi, Toshiaki Enomoto, NAMICS Coporation / Japan
- P11 Influence of Module Structure on Reliability of Silicon Solar Cells**
Taeko Semba¹, Genki Saito¹, Shuichi Asao², Katsuhiko Shirasawa², Hidetaka Takato², ¹NAMICS Corporation / Japan, ²AIST / Japan
- P12 Characteristics of Nickel Thin Film Electroplated by Supercritical CO₂ Emulsion Assisted with Ultrasonic Agitation**
H. C. Chuang¹, C. H. Huang¹, A. H. Liao², ¹National Taipei University of Technology, ²National Taiwan University of Science and Technology / Taiwan
- P13 Electromechanical Reliability of Flexible Transparent Electrode of Gravure Offset Printed Invisible Silver-Grid Laminated with Conductive Polymer**
Masato Ohsawa, Natsuki Hashimoto, ULVAC, Inc. / Japan
- P14 High Thermal Conductivity Composite Resin Sheet Filled with Large Diameter Aluminum Nitride and Aggregated Boron Nitride**
I. Masada, S. Fujii, S. Imazumi, K. Fujinami, Y. Kanechika, T. Nawata, M. Ueda, Tokuyama Corporation / Japan
- P15 Preparation of Si-Ti Based Nanofibers and Thin Film by Single-Needle Electrospinning**
Wen-Yu Wang, Huai-You Lee, Cho-Liang Chung, I-Shou University / Taiwan
- P16 A Hollow Nanostructure of Silicon-Based Can be Produced by Using Electrospinning Process**
Chun-Yi Chen, Jun-Wei Zheng, Kai-Po Hsu, Cho-Liang Chung, I-Shou University / Taiwan
- P17 New Adhesive Design and Evaluation for Bumpless Interconnects and Wafer-On-Wafer (WOW) Integration**
S. Maetani^{1,2}, N. Araki^{1,2}, Y. S. Kim^{1,3}, S. Kodama^{1,3}, T. Ohba¹, ¹Tokyo Institute of Technology / Japan, ²DAICEL Corp. / Japan, ³DISCO Corp. / Japan
- P18 Study of Low-Residual Stress Amorphous Film Deposition Method for LiTaO₃/Quartz or LiNbO₃/Quartz Bonding toward 5G Surface Acoustic Wave Devices**
Ami Tezuka¹, Hiroyuki Kuwae¹, Kosuke Yamada¹, Shuichi Shoji¹, Shoji Kakio², Jun Mizuno^{1,3}, ¹Waseda University, ²Yamanashi University / Japan, ³Soochow University / China
- P19 Result of High Accelerated Stress Test of Organic Substrate Made by Integrated Dry Process.**
Shinichi Endo¹, Shintaro Yabu², Tomoyuki Habu¹, ¹Ushio Inc. / Japan, ²Ushio America Inc. / USA
- P20 Electrodeposition of Cu Doped ZnS and Evaluation of Its Photocatalytic Property**
Naohiro Matsuda, Naoki Okamoto, Takeyasu Saito, Osaka Prefecture University / Japan
- P21 Comparison of Low Temperature Sinterability of Silver Micro-particles in Epoxy-based Binders Containing Several Mercaptocarboxylates**
Shiho Nakazawa, Masahiro Inoue, Gunma University / Japan
- P22 Bonding Strength of Cu-to-Cu Joints Using Cu Cold Spray Deposition by an Oxidation and Reduction Process for Power Device Package**
Juncai Hou^{1,2}, Chengxin Li³, Sijie Huang², Hiroshi Nishikawa², ¹ShaanXi University of Technology / China, ²Osaka University / Japan, ³Xi'an Jiaotong University / China
- P23 Suppression of Backside Damage in Stealth Dicing**
Natsuki Suzuki^{1,2,3}, Takayuki Ohba¹, ¹Tokyo Institute of Technology, ²Hamamatsu Photonics K.K., ³The Graduate School for the Creation of New Photonics Industries / Japan
- P24 Structural Analysis and Electric Double Layer Capacitor of Furfural Resin -Based Active Carbon with Different Particle Size**
Kanade Hokari¹, Shinichiro Suzuki¹, Naoki Okamoto¹, Takeyasu Saito¹, Isamu Ide², Masanobu Nishikawa², Yoshikazu Onishi², ¹Osaka Prefecture University, ²LIGNYTE. CO., LTD. / Japan
- P25 High Temperature Dielectric Property of Silicon Nitride Insulating Substrate for Next Generation Power Module up to 350 Degrees Celsius.**
Tsuyoshi Abe, Yasutaka Nishigaki, Masahiro Kozako, Masayuki Hikita, Kyushu Institute of technology / Japan
- P26 Characterization of Thermal-Electric Performance of Silicon Power MOSFET Inverter Using Coupled Field Analysis**
Y.-S. Liao¹, Y.-H. Shen¹, H.-C. Cheng², W.-H. Chen¹, ¹National Tsing Hua University, ²Feng Chia University / Taiwan